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STC ANNOUNCES SECOND GLOBAL CONFERENCE IN RESPONSE TO UNPARALLELED INDUSTRY-WIDE DEMAND FOR FOLLOW-UP EVENT

NIWOT, Colorado, April 11, 2007 — The Semiconductor Test Consortium, Inc. (STC), the leading proponent of worldwide adoption of Open Architecture, today announced that due to industry-wide demand, the consortium will host the second Global STC Conference (GSC). Open to all STC members as well as other semiconductor, equipment and instrumentation companies, the annual test solutions-focused event is expected to draw more than the 126 international attendees from 59 companies it drew last year. The conference will enable this ecosystem of vendors, third party developers, standards groups and universities to collaborate on how to deliver technical and economic benefits to the global semiconductor industry through development of industry-wide standards.

The second annual GSC (formerly called the Global OPENSTAR Conference) will be held from May 14 through 16, 2007, at the Napa Valley Marriott Hotel in Napa, Calif. Building on the success of last year's event, the May 14 opening day agenda will focus on the "Industry Trends: A Global Perspective," which will include a keynote address given by Dan Hutcheson, CEO of VLSI Research, Inc., ITRS Roadmap presentation, Cost of Ownership case study and industry panel discussion comprised of leading analysts. The May 15 agenda will highlight presentations from five prominent semiconductor manufacturers including Infineon, Intel, Renesas, Texas Instruments and Toshiba, and leading ATE companies including Advantest, LTX, Teradyne and Verigy, centered on the "Test Challenges, Expectations and Solutions" theme. On May 16, closing day of the conference, the "Enabling the Ecosystem" topic will be addressed by STC technical working groups and additional selected presenters, including IBM.

"During a time when the global, consumer driven nature of the semiconductor industry is placing overwhelming demands on the test industry, it is no surprise that we have received such a tremendous amount of support and requests to host the second annual Global STC Conference," explained Keith Imai, GSC Chairman. "We are encouraged by the list of outstanding speakers scheduled for the event, in addition to the exceptional interest to advance the open architecture framework and test solutions in and around the ATE infrastructure to meet the ever-changing demands of the semiconductor industry."

For additional details in addition to hotel and conference registration, please visit:
<http://www.semitest.org/events/gscwebpage/>

The STC will hold the next general meeting on June 26 in Reutlingen, Germany, which will be hosted by Robert Bosch GmbH.

About the Semiconductor Test Consortium

The Semiconductor Test Consortium was founded in 2003 to develop a common test architecture that is completely open, documented and supported via solutions available from all ATE vendors. Open to all companies throughout the semiconductor supply chain with a vested interest in the test sector, the consortium is focused on the following goals: formalizing a broadened STC scope with new working groups and specification structure; fostering pre-competitive collaboration among industry participants toward development of value-added standards; emphasizing new initiatives, the value of work being accomplished and the contributions to the industry; and continuing STC efforts to fully enable the OPENSTAR[®] Ecosystem. Today, 45 semiconductor, equipment and instrumentation companies worldwide and 40 university members in Europe, Japan, China and the United States, in addition to seven STIL users and six individuals support the STC. More information can be found at www.semitest.org

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